10/532809

## PATENT APPLICATION

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

JC12 Rec'd PCT/PTC 2 6 APR 2005

Seiji YAMADA

Application No.: New U.S. National Stage of PCT/JP03/13414

Filed: April 26, 2005 Docket No.: 123655

For: FORMING DIE FOR CONTACT LENS AND CONTACT LENS MANUFACTURING

METHOD USING THE FORMING DIE

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- Relevance of references 7-10, 12-13 is discussed in the present specification.
- 3. References 5-6, 15-16 were cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 5. English language Abstracts of references 7-10, 12-13, and 16 are attached hereto.
- 6. Computer-generated English language translations of the following Japanese references have been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and are attached, but have not been reviewed for accuracy. See References 10, 12, and 16.
- 7. References 1 and 2 correspond to Reference 7. Reference 3 corresponds to Reference 8. Reference 4 corresponds to Reference 9. Reference 11 corresponds to Reference 10. Reference 14 corresponds to Reference 13.

Respectfully submitted,

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Date: April 26, 2005

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Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461

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DATE CONSIDERED

ATTY DOCKET NO. Form PTO-1449 US Dept. of Commerce PATENT & TRADEMARK OFFICE (REV. 8-83) 123655 New U.S. National Stage of PCT/JP03/13414 INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) **APPLICANT** Seiji YAMADA **FILING DATE GROUP** April 26, 2005 U.S. PATENT DOCUMENTS **EXAMINER** SUB INITIAL DOCUMENT NUMBER DATE NAME **CLASS** CLASS 09/12/1978 James A. CLARK et al. 1. 4,113,224 2. 4,197,266 04/08/1980 James A. CLARK et al. 3. 4,209,289 06/24/1980 Paul D. NEWCOMB et al. 4. 09/01/1992 Ronald S. HAMILTON et al. 5,143,660 5. 04/13/1999 Karlheinz BONEBERGER et al. 5,894,002 5,271,875 12/21/1993 William J. APPLETON et al. 6. FOREIGN PATENT DOCUMENTS SUB DOCUMENT NUMBER DATE **COUNTRY CLASS CLASS** 7. JP-A-50-151966 w/ abst. 12/06/1975 **JAPAN** 8. JP-A-55-151618 w/ abst. 11/26/1980 **JAPAN** 9. JP-A-02-172712 w/ abst. 07/04/1990 **JAPAN** 10. JP-A-06-208090 w/ abst. & trans. 07/26/1994 **JAPAN** EP 0 545 720 A1 06/09/1993 **EUROPEAN PATENT OFFICE** 11. JP-A-2000-289041 w/ abst. & trans. 10/17/2000 **JAPAN** 12. 13. JP-A-01-500256 w/ abst. 02/02/1989 **JAPAN** WO 87/04390 A1 07/30/1987 **WIPO** 14. 03/15/2001 **WIPO** 15. WO 01/17756 A1 01/21/2003 **JAPAN** 16. JP-A-2003-019724 w/ abst. & trans. OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: April 26, 2005

**EXAMINER**